

<b>Notice of References Cited</b>	Application/Control No. 10/575,636		Applicant(s)/Patent Under Reexamination HWANG, CHANG-YEOP	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0029498 A1	10-2001	Tomoike, Hiroyuki	705/78
*	B	US-2002/0017561 A1	02-2002	Tomoike, Hiroyuki	235/383
*	C	US-2002/0073027 A1	06-2002	Hui et al.	705/40
*	D	US-2002/0083009 A1	06-2002	Lansing et al.	705/64
*	E	US-2002/0107007 A1	08-2002	Gerson, Howard	455/414
*	F	US-2002/0128929 A1	09-2002	Urabe, Akio	705/26
*	G	US-2002/0147913 A1	10-2002	Lun Yip, William Wai	713/184
*	H	US-6,565,000 B2	05-2003	Sehr, Richard P.	235/384
*	I	US-2003/0097444 A1	05-2003	Dutta et al.	709/225
*	J	US-2003/0158891 A1	08-2003	Lei et al.	709/203
*	K	US-6,609,658 B1	08-2003	Sehr, Richard P.	235/384
*	L	US-2004/0002917 A1	01-2004	Horn et al.	705/39
*	M	US-2004/0068448 A1	04-2004	Kim, Min-Suh	705/027

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Merriam-Webster Dictionary, 9th ed., 1991. Def. "associate"
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0083168 A1	04-2004	Kuth et al.	705/040
*	B	US-2005/0075958 A1	04-2005	Gonzalez, Edwin	705/035
*	C	US-2005/0086164 A1	04-2005	Kim et al.	705/040
*	D	US-6,910,628 B1	06-2005	Sehr, Richard P.	235/384
*	E	US-2005/0187873 A1	08-2005	Labrou et al.	705/040
*	F	US-2005/0203854 A1	09-2005	Das et al.	705/064
*	G	US-2005/0224575 A1	10-2005	Gray, R. O'Neal	235/380
*	H	US-2006/0106699 A1	05-2006	Hitalenko et al.	705/035
*	I	US-2007/0005492 A1	01-2007	Kim, Min-Suh	705/039
*	J	US-7,275,685 B2	10-2007	Gray et al.	235/380
*	K	US-7,308,424 B2	12-2007	Urabe, Akio	705/26
*	L	US-2007/0299739 A1	12-2007	Urabe, Akio	705/026
*	M	US-2008/0048025 A1	02-2008	Fitzgerald et al.	235/380

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

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	U	
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	W	
	X	

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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,343,344 B2	03-2008	Tomoike, Hiroyuki	705/39
*	B	US-7,428,507 B2	09-2008	Villaret et al.	705/37
*	C	US-7,487,126 B2	02-2009	Kwan, Khai Hee	705/39
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
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